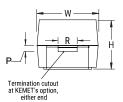


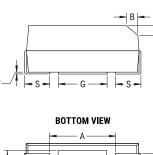
T541X227K016DT8510

T541 HRA, Tantalum, Polymer Tantalum, HRA Multi-Anode, 220 uF, 10%, 16 VDC, SMD, Polymer, Molded, High Reliability, Multi-Anode, Low ESR, D (0.001%/1000 Hrs), 40 mOhms, 7343, 4.3 mm, 1.3 mm

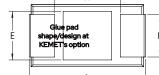
CATHODE (-) END VIEW



ANODE (+) END VIEW



SIDE VIEW



Click here for the 3D model.

General Information	
Series	T541HRA
Dielectric	Polymer Tantalum
Style	SMD Chip
Description	SMD, Polymer, Molded, High Reliability, Multi-Anode, Low ESR
Features	Non-Combustible, Multiple Anode, Low ESR, High Reliability
RoHS	Yes
Termination	Tin
AEC-Q200	No
Typical Component Weight	410.89 mg
Shelf Life	52 Weeks
MSL	3

Dimensions	
L	7.3mm +/-0.3mm
W	4.3mm +/-0.3mm
Н	4mm +/-0.3mm
т	0.13mm REF
S	1.3mm +/-0.3mm
F	2.4mm +/-0.1mm
A	3.8mm MIN
В	0.5mm +/-0.15mm
E	3.5mm REF
G	3.5mm REF
Р	1.7mm REF
R	1mm REF
Х	0.1mm +/-0.1mm REF

Packaging Specifications	
Packaging	T&R, 178mm
Packaging Quantity	500

Specifications	
Capacitance	220 uF
Tolerance	10%
Voltage DC	16 VDC (105C), 10.72 VDC (125C)
Temperature Range	-55/+125°C
Rated Temperature	105°C
Life	2000 Hrs (125C)
Humidity	85C, 85% RH, 1000 Hours, rated voltage
Dissipation Factor	10% 120Hz 25C
Failure Rate	D (0.001%/1000 Hrs)
ESR	40 mOhms (100kHz 25C)
Ripple Current	2598 mA (rms, 100kHz 45C)
Leakage Current	352 uA (5min 25°C)
Testing and Reliability	4 Cycles At 25C +/-5C & Improved Humidity Capability

Statements of suitability for certain applications are based on our knowledge of typical operating conditions for such applications, but are not intended to constitute - and we specifically disclaim - any warranty concerning suitability for a specific customer application or use. This Information is intended for use only by customers who have the requisite experience and capability to determine the correct products for their application. Any technical advice inferred from this Information or otherwise provided by us with reference to the use of our products is given gratis, and we assume no obligation or liability for the advice given or results obtained.